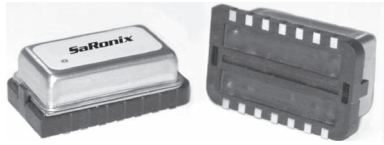


Technical Data

STA / STT Series



Description

A crystal controlled, low current, low jitter and high frequency oscillator with precise rise and fall times demanded in high performance networking, telecom and processor applications. The tri-state function enables the output to go high impedance. Available in a 14 or an 8 pin DIP compatible, resistance welded, all metal case. Pin 7 (or Pin 4) is grounded to case to reduce EMI. See photo above for new, full size metal package with a true SMD adapter. For this package option select option S in part number builder.

Applications & Features

- Fibre Channel
- Gigabit Ethernet
- High performance Processors
- True SMD DIL14 version available
- High Drive HCMOS, ACMOS or TTL capability
- Tri-State output
- Precise Rise/Fall Times
- Reduced EMI circuitry
- Short circuit protected output

Frequency Range:	STT 5V	STA 5V	STA 3.3V
Full Size:	250kHz - 135MHz	125kHz - 135MHz	125kHz - 125MHz
Half Size:	250kHz - 135MHz	500kHz - 135MHz	500kHz - 125MHz

Frequency Stability:	±20, ±25, ±50 or ±100 ppm over all conditions: calibration tolerance, operating temperature, rated input voltage change, load change, aging*, shock and vibration
* 1 year @ +40°C	

Temperature Range:	
Operating:	0 to +70°C or -40 to +85°C
Storage:	-55 to +125°C

Supply Voltage:	
Recommended Operating:	+5V ±10% or 3.3V ±10% (STA only)

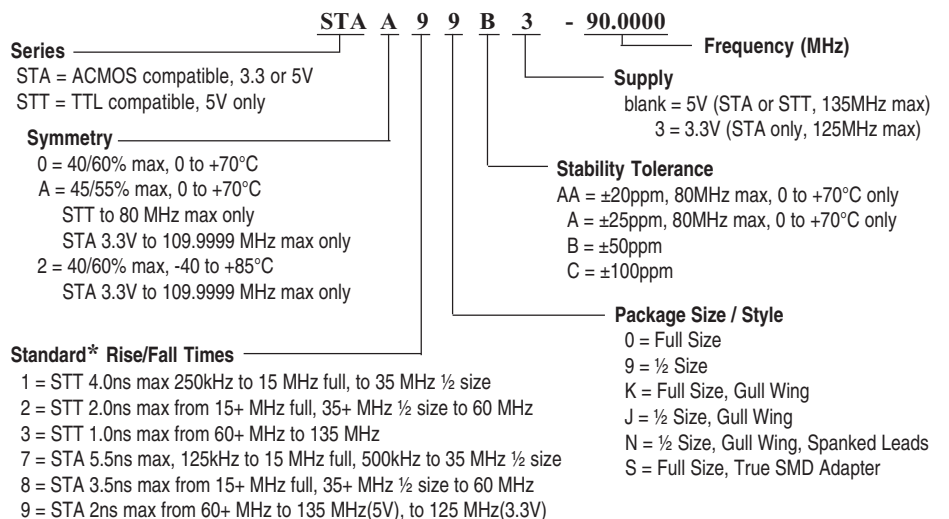
Supply Current:	50mA typ, 70mA max @ 5V or 30mA typ, 45mA max @ 3.3V
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Output Drive:	
ACMOS / TTL	
Symmetry:	See Part Numbering Guide
Rise & Fall Times:	See Part Numbering Guide
Logic 0:	10% VDD or 0.5V max
Logic 1:	90% VDD or 2.5Vmin
Load:	50Ω ACMOS, 95Ω ACMOS @ 3.3V, 50mA sink & source @ TTL
Period Jitter RMS:	8ps max

Mechanical:	
Shock:	MIL-STD-883, Method 2002, Condition B
Solderability:	MIL-STD-883, Method 2003
Terminal Strength:	MIL-STD-202, Method 211, Conditions B2
Vibration:	MIL-STD-883, Method 2007, Condition A
Solvent Resistance:	MIL-STD-202, Method 215
Resistance to Soldering Heat:	MIL-STD-202, Method 210, Condition A, B or C

Environmental:	
Gross Leak Test:	MIL-STD-883, Method 1014, Condition C
Fine Leak Test:	MIL-STD-883, Method 1014, Condition A2
Thermal Shock:	MIL-STD-883, Method 1011, Conditions A
Moisture Resistance:	MIL-STD-883, Method 1004

Part Numbering Guide



*R/F times are standard with given frequency ranges, non-standard R/F times available on some models, please contact SaRonix

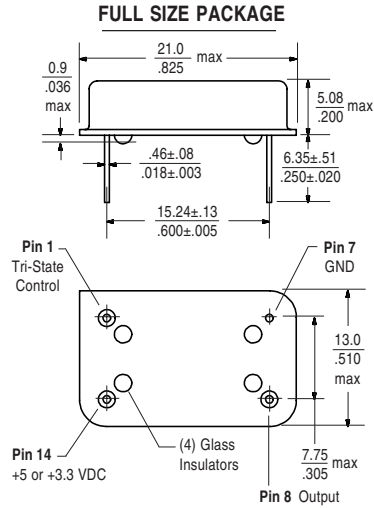
Example PN: STT220C - 60.0000

DS-108 REV K

Technical Data

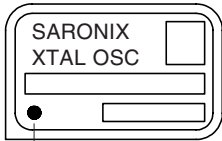
STA / STT Series

Package Details

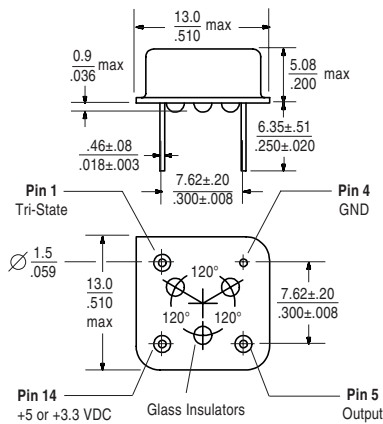


Marking Format **

Includes Date Code, Frequency & Part Number



HALF SIZE PACKAGE



Marking Format **

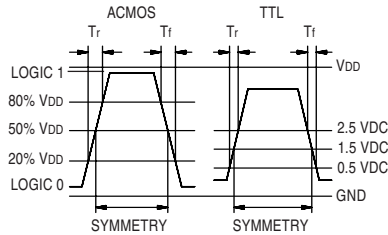
Includes Date Code, Frequency & Part Number



** Exact location of items may vary

Scale: None (Dimensions in mm / inches)

Output Waveform

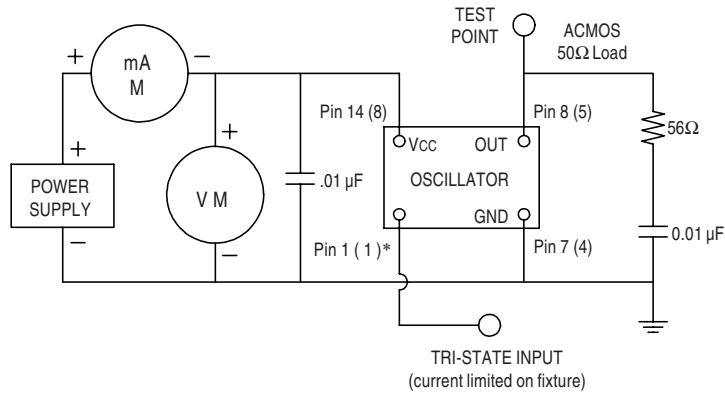


Tri-State Logic Table

Pin 1 Input	Output Standard Logic
Logic 1 or NC	Oscillation
Logic 0 or GND	High Impedance

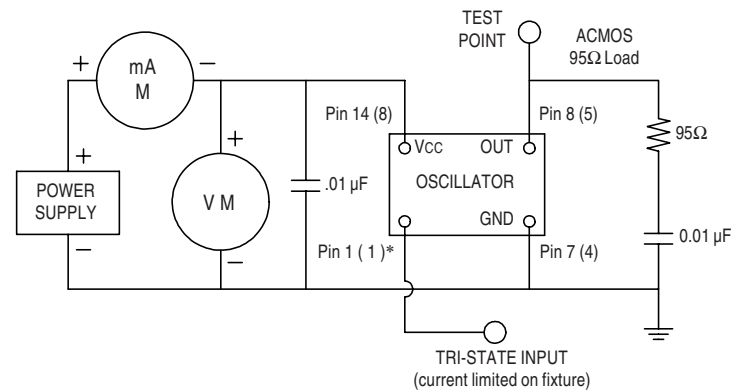
Required Input Levels on Pin 1:
Logic 1 = 2.2V min
Logic 0 = 0.8V max

Test Circuit



* () Indicates pin numbers for half-size package

50Ω AC MOS TEST CIRCUIT (5V operation)



* () Indicates pin numbers for half-size package

95Ω AC MOS TEST CIRCUIT (3.3V operation)

All specifications are subject to change without notice.